

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/563,030	STEFFEN ET A	L.
Examiner	Art Unit	
Muhammad Akbar	2618	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Words searchs in EASt using class 455/423,425,67.11 (attached searh history)	8/27/2007	MA
Words searchs by using keywords wireless device under test for measuring high frequency	8/27/2007	MA
IEEE/WIPO/EPO documents searches by using keywords wireless device under test for measuring high frequency	8/31/2007	MA
		